



P/1071-1593 CIP

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Gaku KAMITANI

Date : July 28, 2004

Serial No. : 10/601,718

Group Art Unit : 2863

Filed : June 23, 2003

Examiner : Michael P. Nghiem

Confirmation No. : 8700

For : METHOD FOR CORRECTING MEASUREMENT ERROR,
METHOD OF DETERMINING QUALITY OF ELECTRONIC
COMPONENT AND DEVICE FOR MEASURING
CHARACTERISTIC OF ELECTRONIC COMPONENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

JP H08-15348 was cited and made of record in the parent case, U.S. Patent 6,697,749.

An English-language abstract is enclosed.

The other enclosure is the published manual described in the specification under "Description of the Related Art." A translation is enclosed.

The Examiner is requested to sign and return the enclosed form to the undersigned.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on July 28, 2004:

James A. Finder

Name of applicant, assignee or
Registered Representative

Signature

July 28, 2004

Date of Signature

Respectfully submitted,

James A. Finder

Registration No.: 30,173

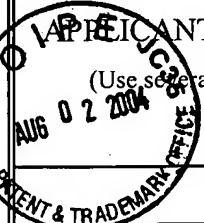
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 <p>APPLICANT'S ART CITATION (Use several sheets if necessary)</p>		Application 10/601,718		OFGS File No. P/1071-1593 CIP			
		Applicant Gaku KAMITANI					
		Filing Date June 23, 2003		Group Art Unit 2863			
		U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)					
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	08-015348	01-1996	Japan			x	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
		HP 4284A Precision LCR Meter Instruction Manual, pp. 6-14 to 6-19 (December 1966)					
Examiner		Date Considered					
<small>EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.</small>							